Monte Carlo Simulation Study of Cs₂Te

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Introduction



Several experiments have been devoted to characterizing Cs_2Te photocathodes in terms of quantum yield and thermal emittance.

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Monte Carlo simulation was applied to simulate the quantum yield dependence on photon energy in Cs_2Te and the transverse emittance dependence on the electron affinity.

Band structure and Density of states – Cs₂Te





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Orthorhombic crystal structure Space group pnma (62)

	DFT	Ref (6)	EXP (5)
a (Å)	5.844	5.845	5.871
b (Å)	9.415	9.542	9.109
c (Å)	11.663	11.591	11.474

Band structure and Density of states – Cs₂Te

- A parabolic fit was used to calculate the effective mass using the curvature of the fit.
- The effective mass at the Fermi energy can calculate using



$$m^* = \hbar^2 (\frac{d^2 E}{dk^2}_{k=k_f})^{-1}$$

Direction	ΓX direction	
Γ <i>X</i> direction	0.27 m ₀	
ΥΓ direction	0.25 m ₀	
ΓZ direction	0.27 m ₀	

Electron effective mass roughly estimated using

$$m^* = \frac{E_g m_0}{R_\infty},$$

where m_0 - electron effective mass and R_{∞} - Rydberg Constant 13.606 eV E_g - band gap.

 According to the above equation m^{*} is 0.2425 and this value is very close to the DFT calculated effective mass.

Three-step model



(i) Finally, the electrons escape into the vacuum.

Absorption profile – Cs₂Te



Absorption profile curve for Cs_2Te bulk and Cs_2Te/Mo interface with a Cs_2Te thickness of 30nm. Inset- reports the reflectance (R), transmission (T), and absorption (A) of Cs_2Te/Mo as function of Cs thickness. • The absorbed laser energy decays exponentially along the cathode's thickness.

$$F(s) = F_0 e^{-\alpha(\omega)s}$$

- Absorption coefficient $\alpha(\omega)$ depends on the wavelength.
- The absorption coefficient $\alpha(\omega)$ 0.0577 was obtained by interpolating the figure on the left side [03].
- In this simulation, I consider 15 nm thickness.
- Assumption 1 The absorption coefficient is constant for all photon energies.
- Far from the threshold region, the absorption should not vary significantly.

Initial parameters for an electron

- Assumption 2 Each photon (no photon=2*10⁵) emits an electron from the valence band.
- The Density of states (DOS) of the valence band is used to select the number of electrons.
- Conduction band minimum set as the energy zero point.
- This simulation uses the experimental band gap energy (3.3 eV) value.
- Conduction band energy = VB energy + Photon energy Band gap.
- The position of an electron is calculated using the Monte Carlo simulation.
- $F(s) = \alpha(\omega)e^{-\alpha(\omega)s}$ is the distribution of the position of excited electrons.
- The initial direction was selected using the Monte Carlo simulation assuming all the directions are isotropic.

Distributions for initial variables



Inter valley scattering

- If photon energy is greater than 2*band gap (E_q) the electron-electron scattering dominates.
- For photon energies less than $2E_g$ e-e scattering has a very low probability and electron energy reduces due to electron-phonon scattering.
- For simplicity, only optical phonon scattering and inter valley phonon scattering considered.
- When electrons' energy is high enough to scatter into other valleys, inter valley scattering dominates.
- Inter valley scattering rate

$$\lambda_{i\pm}(E) = \frac{D_i^2 m^{*\frac{3}{2}} (N_q + \frac{1}{2} \mp \frac{1}{2})}{\sqrt{2}\pi\hbar^2 \rho E_{ph}} (E \pm E_{ph})^{\frac{1}{2}}$$

+/- - absorption and emission

 E_{ph} – phonon energy

 D_i – deformation potential 1x10⁹ eV/cm

ho – density of material

Polar optical phonons

- Electrons lie in one band; polar optical phonon scattering is the dominant process.
- Polar optical phonon scattering rate

$$\lambda_{0\pm}(E) = \frac{e^2 m^{*\frac{1}{2}} E_{ph}(N_q + \frac{1}{2} \mp \frac{1}{2})}{4\sqrt{2}\pi\hbar^2 \mathcal{E}_0 \mathcal{E}_p E^{\frac{1}{2}}} ln \left| \frac{(E \pm E_{ph})^{\frac{1}{2}} + E^{\frac{1}{2}}}{(E \pm E_{ph})^{\frac{1}{2}} - E^{\frac{1}{2}}} \right|_{k=1}^{\infty}$$

$$\varepsilon_p = \frac{1}{\frac{1}{2}} \frac{1}{\varepsilon_{\infty} - \frac{1}{\varepsilon_s}}$$

• The Occupation number of the phonon follows the Bose-Einstein statics,

$$N_q = \frac{1}{\exp(E_{ph}/k_B T) - 1}$$

+/- - absorption and emission

 E_{ph} – phonon energy

 $\boldsymbol{\epsilon}_{\infty},\boldsymbol{\epsilon}_{s}$ - high frequency and static dielectric constant

Phonon scattering cont.

- Scattering rate $\lambda(E) = \lambda_{0-} + \lambda_{0+}$, for electrons with energy lower than the minimum of the second lowest band.
 - λ_{0-}/λ , is the possibility of emitting an electron and energy loss E_{ph} .
 - λ_{0+}/λ , is the possibility of absorbing an electron and energy absorption E_{ph} .
- Scattering rate $\lambda(E) = \lambda_{0-} + \lambda_{0+} + \lambda_{i-} + \lambda_{i+}$, for electrons with higher energy.
 - $(\lambda_{0-}+\lambda_{i-})/\lambda$, is the possibility of emitting an electron and energy loss E_{ph} .
 - $(\lambda_{0+}+\lambda_{i+})/\lambda$, is the possibility of absorbing an electron and energy absorption E_{ph} .
- The probability for an electron to travel a distance d without suffering a scattering event is $P(\lambda) = \exp\left(-\frac{d}{\lambda}\right)$, where λ is the electron's mean free path.
- After scattering, the change of direction is not isotropic.
- The polar angle θ between the original and the new trajectory and the azimuthal angle φ will follow the distributions,

$$g_1(\theta) \propto \frac{\sin \theta}{E + (E \pm E_{ph}) - 2\sqrt{(E(E \pm E_{ph})\cos\theta)}},$$
$$g_2(\varphi) = \frac{1}{2\pi}.$$

Energy Distribution

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Photon energy =4.83 eV



The left side picture represents the energy distribution in the conduction band before scattering. The right-side figure represents the energy distribution after scattering.

Transmission probability

$$T(E, s, x, \xi, E_a) = D((E - \Delta E)x^2 + E_b, \xi, E_a)$$
$$D(E, \xi, E_a) = \frac{2}{1 + \frac{(H(E) + E)}{2\sqrt{EH(E)}}} [e^{\theta(E)} - \frac{1}{4}(1 - e^{-\theta(E)})]$$

$$\theta(E) = \begin{cases} 0 & E > E_a \\ \frac{2}{\hbar e\xi} \sqrt{2m^*(E_a - E)^3} & E \le E_a \end{cases}$$

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$$H(E) = \sqrt{(E - E_a)^2 + (f_0^2 \hbar^2 (e\xi)^2 / 2m^*)^{\frac{2}{3}}},$$

 f_0 -dimensionless number 0.51697 ξ - electric field $\alpha(\omega)$ - absorption coefficient ΔE – energy loss

- When the electrons approach the surface, they will traverse the band bending region and obtain extra E_b in the longitudinal direction and the Schottky reduction E_{sch}.
- The quantum efficiency is calculated using the number of scattered electrons and the no of photons.
- Reflection, absorption, and transmission possibilities are considered to calculate the number of electrons.

 $QE = \frac{(1-R)*(1-\exp(\alpha T))*scatterd and emitted electrons}{No of photons absorbed}$

Thermal Emittance

• The transverse momentum conservation law at the surface,

 $P_{trans}^{in} = P_{trans}^{out}$ $P^{out} = \sqrt{(2m_0(E + E_b + E_{sch}))}$ $P_{trans}^{out} = \sqrt{(2m_0(E + E_b + E_{sch})sin\theta cos\phi)}$ $E_{trans} = \sqrt{(2m_0(E + E_b + E_{sch})sin\theta cos\phi)}$

$$E_{sch} (eV) = 0.038 \sqrt{E(MV/m)}$$

 $P^{out} > P^{out}_{trans}$

- The normalized transverse rms emittance may be deduced by measuring the rms beam divergence at the cathode for a given beam spot size.
- The normalized transverse rms emittance is defined as

$$\epsilon_{n,rms} = \frac{1}{m_0 c} \sqrt{\sigma^2(x) \sigma^2(p_x) - \sigma^2(x p_x)}$$

• The correlation term $\sigma^2(xp_x)$ vanishes at the source since the quantities x and p_x are uncorrelated.

$$\epsilon_{n,rms} = \frac{1}{m_0 c} p_{x,rms} \times x_{rms}$$

Normalized Transverse Momentum Distribution

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The probability distribution for the normalized transverse momentum at the cathode for photo-emitted electrons. A bin of 1×10^{-5} is used for the normalized transverse momentum. Laser spot size 1.5 mm.

Constants used in this simulation

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Band gap E _g	3.3 eV
Electron affinity E _a	0.25 eV
Band bending energy E _b	0.05 eV
Effective mass m*	0.7 m ₀
Reflectivity R	20 %
Thickness I	15 nm
Phonon energy E _{ph}	0.04 eV
Static dielectric constant \mathcal{E}_{∞}	3
High frequency dielectric constant \mathcal{E}_s	5.76
Density of material $ ho$	3.99 gcm ⁻³

Quantum Efficiency and Thermal Emittance

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Electric Field= 0 MVm⁻¹



Thermal emittance and QE at 15 nm

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Photon Energy =4.83 eV



Comparison between the simulation results, and the experimental data in Thermal emittance and QE for Cs_2Te at 4.83 eV. The thickness of the photocathode is 15 nm.

Response time- Cs₂Te

Electric Field = 20 MVm⁻¹ and Photon Energy= 4.83 eV



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Band Bending Effect

Photon Energy = 4.83 eV



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Valance band

Electron affinity effect

Photon Energy =4.83 eV



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Summary

- Monte Carlo Simulation was used to calculate quantum efficiency and thermal emittance
- The density functional theory calculated DOS distribution incorporated in the simulation.
- The direction change after each scattering event considered in the simulation.
- e- ph scattering is considered and mainly focused on polar optical phonon scattering and intervalley phonon scattering.
- Calculated thermal emittance values and quantum efficiency values agree with the experimental values.
- The response time is 200.7 fs at a 20 MVm⁻¹ electric field and 4.83 eV photon energy.

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